EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	6974	382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/31 14:40
L2	712	reference near3 compar$3 and L1	US-PGPUB; USPAT	OR	ON	2007/01/31 15:18
L7	5725702	anomaly defect imperfection blemish crack deformity error fault flaw hole irregular$7 scratch contamina$5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/31 15:19
L9	1001769	photomask lithograph$3 semiconductor near mask pcb circuit near2 board reticle wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/31 15:23
L10	144	reference near3 compar$3 with L7 and L1 and L9 near3 7	US-PGPUB; USPAT	OR	ON	2007/01/31 15:52
L13	1981	(bin binning) with region	US-PGPUB; USPAT	OR	ON	2007/01/31 15:54
L14	12	1 and 13	US-PGPUB; USPAT	OR	ON	2007/01/31 15:56
L15	182	(high bright) with (low dark) with (filter$3 remov$3) with (pre-process$3 preprocess$3)	US-PGPUB; USPAT	OR	ON	2007/01/31 15:58
L16	1	1 and 15	US-PGPUB; USPAT	OR	ON	2007/01/31 15:58
L17	29	"382".clas. and 15	US-PGPUB; USPAT	OR	ON	2007/01/31 16:03
L18	12091	(multiple many several array) near3 (CCD sensor detector) with pixel	US-PGPUB; USPAT	OR	ON	2007/01/31 16:04
L19	157	1 and 18	US-PGPUB; USPAT	OR	ON	2007/01/31 16:13
L20	1225	flag$3 with review$3	US-PGPUB; USPAT	OR	ON	2007/01/31 16:38
L21	15	1 and 20	US-PGPUB; USPAT	OR	ON	2007/01/31 16:44

L22	267	(remov$3 filter$3) with (high same low) near3 intensity	US-PGPUB; USPAT	OR	ON	2007/01/31 16:48
L23	28	"382".clas. and 22	US-PGPUB; USPAT	OR	ON	2007/01/31 16:45
L24	49	(threshold$3) with (high same low) near3 intensity and "382".clas.	US-PGPUB; USPAT	OR	ON	2007/01/31 16:49
L25	9	(threshold$3) with (high same low) near3 intensity and 1	US-PGPUB; USPAT	OR	ON	2007/01/31 16:50
L27	40	24 not 25	US-PGPUB; USPAT	OR	ON	2007/01/31 16:51
L32	60928	"382".clas. 1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/31 17:12
L33	246	(remov$3 filter$3 threshold$3) near3 (dark same bright)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/31 17:13
L34	12	(remov$3 filter$3 threshold$3) near3 (high same low) near3 (brightness lightness) and 32	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/31 17:13
L35	55	33 and 32	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/31 17:18
L36	9	35 and 1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/31 17:18
S1	13	peterson near2 ingrid.in. hoff near2 (mike michael).in. wiley near2 jim. in.	US-PGPUB; USPAT	OR	OFF	2007/01/31 14:39

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S2	4	"6268093".pn. "6373975".pn. "6701004".pn. "5965306".pn.	US-PGPUB; USPAT	OR	OFF	2006/12/27 18:45
S3	1	"20040091142"	US-PGPUB	OR	OFF	2007/01/31 17:04
S5	2480728	focus exposure illumination aperture coherence	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 10:09
S6	5708802	anomaly defect imperfection blemish crack deformity error fault flaw hole irregular$7 scratch contamina$5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 10:12
S7	997466	photomask lithograph$3 semiconductor near mask pcb circuit near2 board reticle wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/17 10:14
S8	11954984	different distinct many several plural$4 var$3 chang$3 distinctive various numerous separate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/17 10:17
S9	273699	S8 near3 S5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/17 10:19
S10	148789	S6 with S7	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/17 10:18

S11	7	(subtract$3 tak$3 adj away remov$3) near3 (non-transient)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 17:40
S12	1	S9 and S10 and S11	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 10:20
S13	10220	S9 and S10	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 10:22
S14	451	(subtract$3 tak$3 adj away remov$3) near3 (hard near3 S6)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 17:43
S15	5	S13 and S14	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 10:25
S16	5708802	anomaly defect imperfection blemish crack deformity error fault flaw hole irregular$7 scratch contamina$5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 17:42
S17	17875	(non-transient hard enduring non-fleeting non-evanescent) near3 S16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:30

S18	453	(subtract$3 tak$3 adj away remov$3) near3 S17	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:30
S19	997466	photomask lithograph$3 semiconductor near mask pcb circuit near2 board reticle wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/17 17:44
S20	38	S19 near3 S16 and S18	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/17 17:44
S21	37975	(transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) near3 S16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/31 12:15
S22	4	("5308722" | "6421457").PN. OR ("6701004").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/01/18 14:24
S23	5711627	anomaly defect imperfection blemish crack deformity error fault flaw hole irregular$7 scratch contamina$5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:30
S24	22954	(transient soft brief fleeting evanescent) near3 S23	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:06

S25	17897	(non-transient hard enduring non-fleeting non-evanescent) near3 S23	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:32
S26	21	(subtract$3 tak$3 adj away remov$3) near3 S25 same S24	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:46
S27	1580	S24 same S25	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:06
S28	6952	382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/18 15:08
S29	5711627	anomaly defect imperfection blemish crack deformity error fault flaw hole irregular$7 scratch contamina$5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:08
S30	22954	(transient soft brief fleeting evanescent) near3 S29	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:08
S31	17897	(non-transient hard enduring non-fleeting non-evanescent) near3 S29	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:08

S32	1580	S30 same S31	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:08
S33	6	S32 and S28	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/18 15:10
S34	1	(transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) and "6701004".pn.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/18 15:34
S35	5725702	anomaly defect imperfection blemish crack deformity error fault flaw hole irregular$7 scratch contamina$5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/31 12:15
S36	212	(transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) near3 S35 and "382".clas.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/31 12:16
S37	1	("2004/0091142").URPN.	USPAT	OR	OFF	2007/01/31 13:33
S38	4	("5308722" | "6421457").PN. OR ("6701004").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/01/31 13:35